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U.S. PATENT DOCUMENTS												
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)												
АМ	70	Bahram Javidi and Takanori Nomura, "Polarization encoding for optical security systems", Optical Engineering vol. 39 no. 9 pp. 2439-2443 (2000),.										
AN	TA	N. Davidson et al., "Realization of perfect shuffle and inverse perfect shuffle transforms with holographic elements", Applied Optics vol. 31 no. 11 pp. 1810-1812 (1992),										
AO	1	Uwe D. Zeitner et al., "Polarization multiplexing of diffractive elements with metal-stripe grating pixels", Applied Optics vol. 38 no. 11 pp. 2177-2181 (1999)										
AP	-22	Gregory P. Nordin et al., "Micropolarizer array for infrared imaging polimetry", Journal of the Optical Society of America vol. 16 no. 5 pp. 1168-1174 (1999)										
	70	Franco Gori, "Measuring Stokes parameters by means of a polarization grating", Optics Letters vol. 24 no. 9 pp. 584-586 (1999)										
	TH	Rigorous Coupled Wave Analysis (RCWA) (M. G. Moharam and T. K. Gaylord, "Rigorous coupled-wave analysis of metallic surface-relief gratings", Journal of the Optical Society of America, part A vol. 3 pp. 1780-1787 (1986).										
	7-	Space-Variant polarization state manipulation with computer generated subwavelength metal stripe gratings Bornzon et al Optics Communications 192 (2001) 169-181										
	PA	Computer-ge Optics Letter	nerated Jan 2	i space-variant p 001 vol. 26	polari	ization eleme	nts with subwave	length m	etal stripes	s, Bomzon	et al	
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